Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/522,468	CHANG, WEI-BIN
Examiner	Art Unit
Leonard Saint-Cyr	2626

SEARCHED				
Class	Subclass	Date	Examiner	
704	1, 4 text search	12/4/2006	LS	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See East search (attached)	12/4/2006	LS
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